

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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		Examiner	Art Unit	Page 1 of 1
		James Phan	2872	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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	U	US 2004/0252178 A1, Yoshikawa et al, Dec. 16, 2004		
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